

Simulation of Gain Optimized Sensors



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Many thanks to Marta Baselga Bacardit and Giulio Pellegrini, CNM-Barcelona, Spain, for their device and design layout contributions. Also to Gian-Franco Dalla Betta and Marco Povoli, INFN/FBK-Trento for access to software and support.

June 4, 2013

22nd RD50 Workshop - Albuquerque



Intro: 4D Detection



- What is 4D detection?
 - Fast timing and precise spatial resolution (10's of ps / um) (Hartmut F.-W. Sadrozinski: UFSD 20th RD50 workshop Bari 2012)
- Necessarily thin (<100um)
 - MIP ionizes less mobile charge.
 - How to increase signal? Charge Multiplication!



Charge Multiplication



- How does it work?
 - Bulk defects affect resistivity / space charge
 - Electric field is amplified as a result
- Can we control doping profile to tune field without irradiation?

- Observed in irradiated detectors in 2010!
- Recently observd in non-irradiated pad sensors
 - Baselga / Pellegrini
 - Kramberger
 - Sadrozinski / Ely
 - G. Casse et al, NIM A 624, 2, (2010) 401-404



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Low Gain Avalanche Detectors (LGAD): Run 6474

Pablo Fernández-Martínez (Feb-2013)









IV Results SCIP Simulated IV ← Simulation Results 1.E-08 - Gain diode curve shows 1.E-09 strange shape, can the Current (arb) "humps" be explained? 1.E-10 Gain - No Gain Diode also ■ No Gain shows similar feature 1.E-11 50 150 0 100 200 Voltage (V) Real Data IV 1.E-05 Real Diode Data \rightarrow No Gain W9-E10 Gain W8-G11 1.E-06 Gain W8-I10 - Gain Diode curve shows humps, though not as many 20 1.E-07 - No Gain Diode shows no 1.E-08 such feature 0 50 100 150 200 Voltage (V) **Colin Parker - SCIPP** 22nd RD50 Workshop - Albuquerque

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CV Results







20V Depletion Region Profile









Varying P+ Diffusion Dose





-P+ Diffusion profile peak (value @ 0um) is altered

- Choose the peak value that most closely resembles real data (3.3e16)

- Can't go too high or else avalanche!

Humps and plateaus vary with
P+ Diffusion Dose



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Electric Field





- Slice under central implant pad

 Field peaks sharply at PN junction

- Peak is relatively constant vs. bias voltage

- Deeper into detector field varies strongly with bias

- At large bias, carrier terminal velocity (~20kV/cm) is theoretically still possible in gain diodes





Future Studies



- Simulate incident radiation / dynamic signals
- Understand IV humps, fit better match to real data
- Optimize P-diffusion profile / dose for high field